CMPE 260 Laboratory Exercise 7 Project 2 - Processor Timing

Andrei Tumbar Performed: May 1st Submitted: May 3rd

Lab Section: 1 Instructor: Moskal TA: Jacob Meyerson Dennis Lam

Lecture Section: 1 Professor: Cliver

By submitting this report, you attest that you neither have given nor have received any assistance (including writing, collecting data, plotting figures, tables or graphs, or using previous student reports as a reference), and you further acknowledge that giving or receiving such assistance will result in a failing grade for this course.

Your Signature:

Introduction

A flip-flop needs a certain amount of time before and after the active clock edge where the input signal must be stable. If the signal is not stable during this period of time the state of the flip-flop may become metastable where the input could be either 0 or 1. The time before the clock edge where the signal must stay constant is called the setup time whereas the time after the clock edge is called the hold time. Violating these two times is usually caused by propagation delays and contamination delays in the logic between flip-flops. The hold time on a flip-flop is usually designed to be near zero so that the circuit designer need not worry about too little logic between registers. The contamination delay on the Baysis 3 board is longer than the hold time meaning that a hold time violation cannot be obtained. The setup time, however, can be violated. If the clock period is too short and the propagation delay in the logic is too high, the setup time will be violated.

Results

To test the clocking limits of the MIPS processor, repeatedly incrementing the clock frequency by 5Mhz was implemented. The starting frequency was 10 MHz.

A table of results was generated to show the success and failure during testing of each clock frequency.

Table 1: Results of MIPS Processor at different clock frequencies

Frequency (MHz)	Result
10	Pass
15	Pass
20	Pass
25	Pass
30	Pass
35	Pass
40	Pass
45	Pass
50	Fail

A post-implementation timing waveform was generated for each of the tested frequencies. The Part A test from Project 1 was used to verify all instruction types.

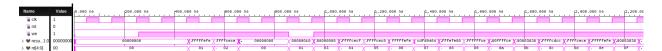


Figure 1: Timing simulation at 10Mhz - Pass

Name	Value	0.000 ns	100.000 ns	200.000 ns	300.000 ns	400.000 ns	580.080 ns	600.00	10 ns	700.000 ns	800.000	ns	900.000 ns	1,000.000 ns	1,100.000 ns	1,200.000 ns	1,300.000 ns	1,480.080 ns 1
1å clk	1																	
¼ rst	0																	
¼ we	1																	
> W result[31:0]	00000000	K	00000000		X.rrrrere X.r	fffcece X. 00	000000	00000010	80800080.X	Y_ffffcecf)	(.FFFFCece) F	ггггеге	Xcdfd9484 X.ff	reress X.rrrrr	ce X DOFFFFce X.	00003030 X. ffffcdc	X.FFFFcece X.FF	rrere X.00003030 Y
> W rd[4:0]	00		00		χ 91 χ.	92 X	00	81	03	X. 84	(95 X.	86	χ 97 χ.	08 X 09	χ. σα χ	9Ь Х. 9с	χ ed χ.	0e

Figure 2: Timing simulation at 15 Mhz - Pass



Figure 3: Timing simulation at $20 \mathrm{Mhz}$ - Pass



Figure 4: Timing simulation at 25Mhz - Pass



Figure 5: Timing simulation at 30Mhz - Pass



Figure 6: Timing simulation at $35 \mathrm{Mhz}$ - Pass



Figure 7: Timing simulation at $40 \mathrm{Mhz}$ - Pass



Figure 8: Timing simulation at $45 \mathrm{Mhz}$ - Pass

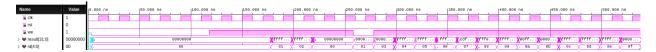


Figure 9: Timing simulation at $50 \mathrm{Mhz}$ - Fail